



TRANSMITTAL OF SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR § 1.97(b), 1.97(c), or 1.97(d)			Attny. Docket No. 2003B001/2
In Re Application of: David G. MARROW et al.			
U.S. Serial No. 10/731,708	Filing Date December 9, 2003	Examiner Not Yet Assigned	Group Art Unit 2857

Address to:
**Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450**

37 CFR § 1.97(b)

- ☒ The Information Disclosure Statement submitted herewith is being filed within three months of the filing date of a national application other than a continued prosecution application under § 1.53(d); within three months of the date of entry of the national stage as set forth in § 1.491 in an international application; before the mailing of a first Office Action on the merits; or before the mailing of a first Office Action after the filing of a request for continued examination under § 1.114.

37 CFR § 1.97(c)

- ☐ The Information Disclosure Statement submitted herewith is being filed after three months of the filing date of a national application other than a continued prosecution application under § 1.53(d); after three months of the date of entry of the national stage as set forth in § 1.491 in an international application; after the mailing of a first Office Action on the merits; or after the mailing of a first Office Action after the filing of a request for continued examination under § 1.114, but before the mailing date of:

1. a Final Action under § 1.113,
2. a Notice of Allowance under § 1.311, or
3. an action that otherwise closes prosecution in the application,

and is accompanied by either:

- ☐ the fee as set forth in § 1.17(p), or
- ☐ the following statement under § 1.97(e)(1): each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

37 CFR § 1.97(d)

- ☐ The Information Disclosure Statement submitted herewith is being filed after a Final Action under § 1.113, a Notice of Allowance under § 1.311, or an action that otherwise closes prosecution in the application, but before, or simultaneously with, the payment of the issue fee. Submitted herewith is the fee as set forth in § 1.17(p) and the following statement under 37 CFR § 1.97(e)(1): each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Applicant hereby request consideration of the Information Disclosure Statement, USPTO form 1449, submitted herewith.

☒ Legible copies of the references are enclosed.

☐ This application is a:

☐ Continuation / Divisional,

☐ Continuation-in-Part,

of U.S.S.N. _____. Copies of the cited references are
☐ enclosed; ☐ not enclosed. References are available in the parent application(s) if not enclosed.

The Commissioner is hereby authorized to charge any additional fees which may be required by this paper, or credit any overpayment, to Deposit Account Number 05-1712. A duplicate copy of this form is enclosed.

31 October 2005

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.		SERIAL NO.	
				2003B001/2		10/731,708	
				APPLICANT			
				David G. MARROW et al.			
FILING DATE		GROUP					
12/09/2003		2857					
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	3,725,378	04/03/1973	Chamberlin			
	AB	3,779,712	12/18/1973	Calvert et al.			
	AC	4,175,169	11/20/1979	Beals et al.			
	AD	4,182,810	01/08/1980	Willcox			
	AE	4,243,619	01/06/1981	Fraser et al.			
	AF	4,469,853	09/04/1984	Mori			
	AG	4,543,399	09/24/1985	Jenkins, III et al.			
	AH	4,588,790	05/13/1986	Jenkins, III et al.			
	AI	4,621,952	11/11/1986	Aronson			
	AJ	4,888,704	12/19/1989	Topliss et al.			
	AK	5,096,634	03/17/1992	Tsadares et al.			
	AL	5,121,337	06/09/1992	Brown			
	AM	5,202,395	04/13/1993	Chambon			
	AN	5,274,056	12/28/1993	McDaniel et al.			
	AO	5,352,749	10/04/1994	DeChellis et al.			
	AP	5,405,922	04/11/1995	DeChellis et al.			
	AQ	5,436,304	07/25/1995	Griffin et al.			
	AR	5,462,999	10/31/1995	Griffin et al.			
	AS	5,589,555	12/31/1996	Zboril et al.			
	AT	5,638,172	06/10/1997	Alsmeyer et al.			
	AU	5,675,253	10/07/1997	Smith et al.			
	AV	5,678,751	10/21/1997	Buchanan et al.			
	AW	5,682,309	10/28/1997	Bartusiak et al.			
	AX	5,696,213	12/09/1997	Schiffino et al.			
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next comment to applicant							

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	6,072,576	06/06/2000	McDonald et al.				
	AB	6,204,664	03/20/2001	Sardashti et al.				
	AC	6,218,484	04/17/2001	Brown et al.				
	AD	6,405,579	06/18/2002	Tjahjadi et al.				
	AE	6,673,878	01/06/2004	Donck				
	AF	2004/0233425	11/25/2004	Long et al.				
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	PUBL. DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AG	EP 238 796	30.09.87	Europe				
	AH	EP 406 805	13.12.95	Europe				
	AI	JP 02038841	1990.02.08	Japan (w/Abstract)				
	AJ	WO 94/21962	29.09.94	PCT				
	AK	WO 96/41822	27.12.96	PCT				
	AL	WO 99/01750	14.01.99	PCT				
OTHER DISCLOSURES (Including Author, Title, Date, Pertinent Pages of Publication, Etc.)								
	AM	K.R. Beebe et al., "An Introduction to Multivariate Calibration and Analysis," Analytical Chemistry, Vol. 59, No. 17, pp.1007A-1017A, Sept. 1, 1987.						
	AN	J. M. Tedesco et al., "Calibration of dispersive Raman Process Analyzers," The Society Of Photo-Optical Instrumentation Engineers, Vol. 3537, pp. 200-212, 1999.						
	AO	G.A. Bakken et al., "Examination of Criteria for Local Model Principal Component Regression," Society for Applied Spectroscopy, Vol. 51, No. 12, pp. 1814-1822, 1997.						
	AP	P. Erlich et al., "Fundamentals of the Free-Radical Polymerization of Ethylene," Advanced Polymer Science, Vol. 7, pp. 386-448, 1970.						
	AQ	M.L. Myrick et al., "In Situ Fiber-Optic Raman Spectroscopy of Organic Chemistry in a Supercritical Water Reactor," Journal of Raman Spectroscopy, Vol. 25, pp. 59-65, 1994.						
	AR	T. Naes et al., "Locally Weighted Regression and Scatter Correction for Near-Infrared Reflectance Data," Analytical Chemistry, Vol. 62, pp. 664-673, 1990.						
EXAMINER					DATE CONSIDERED			
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AA	J.J. Zacca et al., <u>"Modelling of the Liquid Phase Polymerization of Olefins in Loop reactors,"</u> Chemical Engineering Science, Vol. 48, No. 22, pp. 3743-3765, 1993.		
AB	L.P. Russo et al., <u>"Moving-Horizon State Estimation Applied to an Industrial Polymereization Process,"</u> American Control Conf. Proc., San Diego, CA, 1999.		
AC	H. Martens et al., <u>"Multivariate Calibration,"</u> Wiley & Sons Ltd., pp. viii-ix, 1989.		
AD	Multivariate Data Analysis for Windows - Version 3.0, excerpted from Pirouette Software Manual, Exploratory Analysis: Principal Component Analysis, pp. 5-13 through 5-40, 1985-2000.		
AE	E.P.C. Lai et al., <u>"Noninvasive Spectroscopic Detection of Bulk Polymerization by Stimulated Raman Scattering,"</u> Applied Spectroscopy, Vol. 48, No. 8, 1994.		
AF	S. Sekulic et al., <u>"Nonlinear Multivariate Calibration Methods in Analytical Chemistry,"</u> Analytical Chemistry, Vol 65, No. 19, pp. 835A-845A, Oct. 1, 1993.		
AG	E.D. Lipp et al., <u>"On-Line Monitoring Of Chlorosilane Streams By Raman Spectroscopy,"</u> Reprinted from Applied Spectroscopy, Vol 52, No. 1, January, 1998.		
AH	D.R. Battiste et al., <u>"On-Line Raman Analysis of Ethylene and Hexene in the Phillips 1-Hexene and Polyethylene Processes,"</u> Gulf Coast Conference presentation (Abstract)		
AI	M.J. Pelletier et al., <u>"Optical fibers enable Raman instruments to analyze industrial process problems quickly and accurately,"</u> Raman Spectroscopy—Keeps Industry Under Control, Reprint: Photonics Spectra, 4 pgs., October, 1997.		
AJ	V. Centner et al., <u>"Optimization in Locally Weighted Regression,"</u> Analytical Chemistry, Vol. 70, No. 19, pp. 4206-4211, Oct. 1, 1998.		
AK	<u>"Principal Components Analysis,"</u> excerpted from PLS_Toolbox, Version 2.0 Data Analysis Manual, Eigenvector Research, Inc., pp. 32-34, 1998.		
AL	L. Markwort et al., <u>"Raman Imaging of Heterogeneous Polymers: A Comparison of Global versus Point Illumination,"</u> Applied Spectroscopy, Vol. 49, No. 10, pp. 1411-1430, 1995.		
AM	I. Modric et al., <u>"Raman- und Infrarotspektren isotaktischer Polyalkylathylene*,"</u> Colloid & Polymer Sci., Vol. 254, pp. 342-347, 1976.		
AN	M.G. Hansen et al., <u>"Real-Time Monitoring of Industrial Polymers,"</u> Raman Review; pp. 1-4, 3/98.		
AO	S.E. Nave <u>"Rugged Fiber Optic Probes and Sampling Systems for Remote Chemical Analysis Via the Raman Technique,"</u> ISA, Paper #96-042, pp. 453-467, 1996.		
AP	M.J. Pelletier et al., <u>"Shining a Light on Wet Process Control,"</u> Semiconductor International, 4 pages, March, 1996.		
AQ	K.P.J. Williams et al., <u>"Use of Micro Raman Spectroscopy for the Quantitative Determination of Polyethylene Density Using Partial Least-Squares Calibration,"</u> Journal of Raman Spectroscopy, Vol. 26, pp. 427-433, 1995.		
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